Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/509,966	KANEKO, ICHIRO
Examiner	Art Unit
TUAN A. PHAM	2618

	SEAR	CHED	
Class	Subclass	Date	Examiner
455	63.1	6/19/2006	РНАМ
	67.11		
	67.13		
	67.15	-	
	70	6/19/2006	PHAM

INTERFERENCE SEARCHED			
Subclass	Date	Examiner	

DATE 6/19/2006	PHAM
6/19/2006	РНАМ
	_
	-